

MBL400E33D

Silicon N-channel IGBT

FEATURES

- * High thermal fatigue durability.($\Delta T_c=70^\circ\text{C}$, $N>30,000$ cycles)
- * High speed, low loss IGBT module.
- * Low noise due to built-in free-wheeling diode
 - ultra soft fast recovery diode(USFD).
- * Low driving power due to low input capacitance MOS gate.
- * High reliability, high durability module.
- * Isolated heat sink (terminal to base).

ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$)

Item	Symbol	Unit	MBL400E33D
Collector Emitter Voltage	V_{CES}	V	3,300
Gate Emitter Voltage	V_{GES}	V	± 20
Collector Current	DC	I_C	400
	1ms	I_{CRM}	800
Forward Current	DC	I_F	400
	1ms	I_{FRM}	800
Junction Temperature	$T_{vj\text{op}}$	$^\circ\text{C}$	-40 ~ +125
Storage Temperature	T_{stg}	$^\circ\text{C}$	-40 ~ +125
Isolation Voltage	V_{ISO}	V_{RMS}	6,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/22 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value $1.8\pm 0.2/22\pm 1\text{N}\cdot\text{m}$ (2) Recommended Value $5.5\pm 0.5\text{N}\cdot\text{m}$

ELECTRICAL CHARACTERISTICS

1) IGBT+FWD

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	I_{CES}	mA	-	-	12	$V_{CE}=3,300\text{V}$, $V_{GE}=0\text{V}$, $T_{vj}=25^\circ\text{C}$
Gate Emitter Leakage Current	I_{GES}	nA	-500	-	+500	$V_{GE}=\pm 20\text{V}$, $V_{CE}=0\text{V}$, $T_{vj}=25^\circ\text{C}$
Collector Emitter Saturation Voltage	V_{CEsat}	V	3.5	4.2	5.0	$I_C=400\text{A}$, $V_{GE}=15\text{V}$, $T_{vj}=125^\circ\text{C}$
Gate Emitter Threshold Voltage	$V_{GE(th)}$	V	4.5	6.0	7.0	$V_{CE}=10\text{V}$, $I_C=400\text{mA}$, $T_{vj}=25^\circ\text{C}$
Input Capacitance	C_{ies}	nF	-	35	-	$V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{kHz}$, $T_{vj}=25^\circ\text{C}$
Internal Gate Resistance	$R_{G(int)}$	Ω	-	3.6	-	$V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{kHz}$, $T_{vj}=25^\circ\text{C}$
Turn On Delay Time	$t_{d(on)}$	μs	-	0.5	-	$V_{CC}=1,650\text{V}$, $I_C=400\text{A}$
Rise Time	t_r		1.0	1.9	3.1	$L_S=150\text{nH}$
Turn Off Delay Time	$t_{d(off)}$		1.5	2.0	2.6	$R_G=10\Omega$ (3)
Fall Time	t_f		0.5	1.0	2.5	$V_{GE}=\pm 15\text{V}$, $T_{vj}=125^\circ\text{C}$
Forward Voltage Drop	V_F	V	2.0	2.5	3.0	$I_F=400\text{A}$, $V_{GE}=0\text{V}$, $T_{vj}=125^\circ\text{C}$
Reverse Recovery Time	t_{rr}	μs	-	0.6	-	$V_{CC}=1,650\text{V}$, $I_F=400\text{A}$, (4) $L_S=150\text{nH}$, $T_{vj}=125^\circ\text{C}$
Thermal Impedance	IGBT	$R_{th(j-c)}$	-	-	0.026	Junction to case
	FWD	$R_{th(j-c)}$	-	-	0.052	
Contact Thermal Impedance		$R_{th(c-f)}$	-	-	0.016	Case to fin

2) Chopper Diode

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	I_{AKS}	mA	-	-	12	$V_{AK}=3,300\text{V}$, $T_{vj}=25^\circ\text{C}$
Forward Voltage Drop	V_F	V	2.2	2.7	3.2	$I_F=400\text{A}$, $T_{vj}=125^\circ\text{C}$ at main terminals (Terminal resistance:0.5m Ω typical)
Reverse Recovery Time	t_{rr}	μs	0.2	0.6	1.1	$V_{CC}=1,650\text{V}$, $I_F=400\text{A}$, (4) $L_S=150\text{nH}$, $T_{vj}=125^\circ\text{C}$
Thermal Impedance		$R_{th(j-c)}$	-	-	0.052	Junction to case
Contact Thermal Impedance		$R_{th(c-f)}$	-	-	0.016	Case to fin

Notes: (3) R_G value is a test condition value for evaluation, not recommended value.

Please, determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.)with appliance mounted.

(4)Counter arm IGBT $V_{GE}=-15\text{V}$

- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.

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DEFINITION OF TEST CIRCUIT

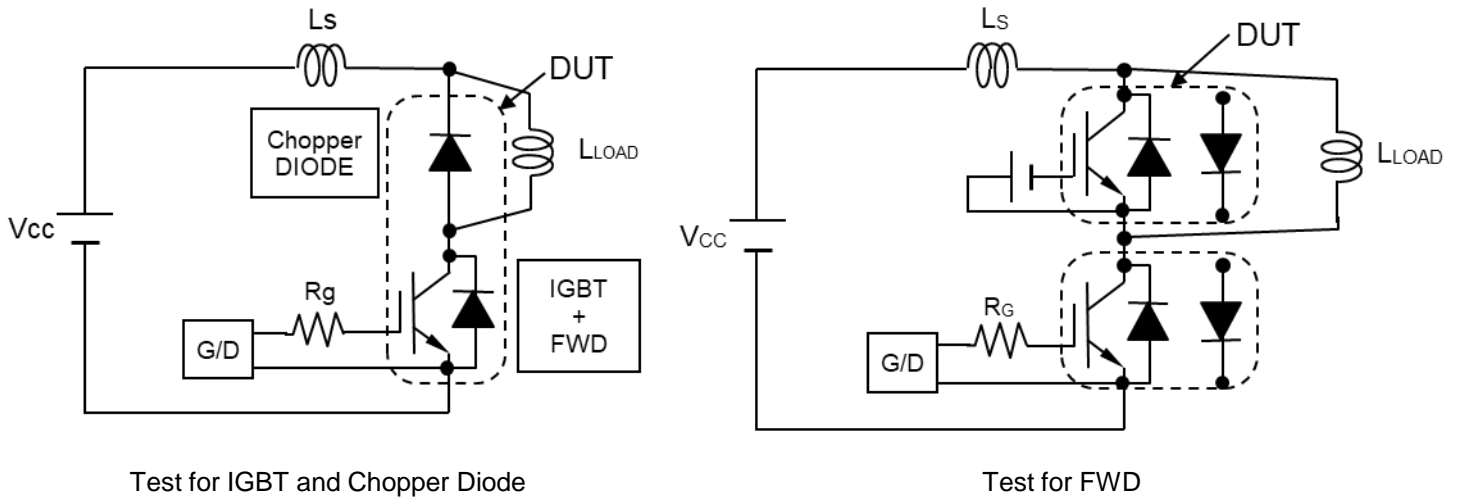


Fig.1 Switching test circuit

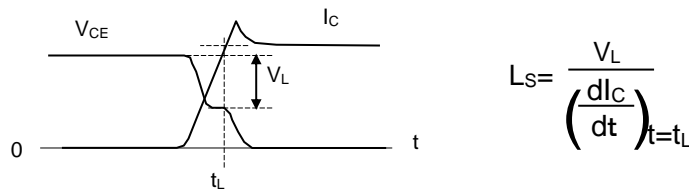


Fig.2 Definition of stray inductance

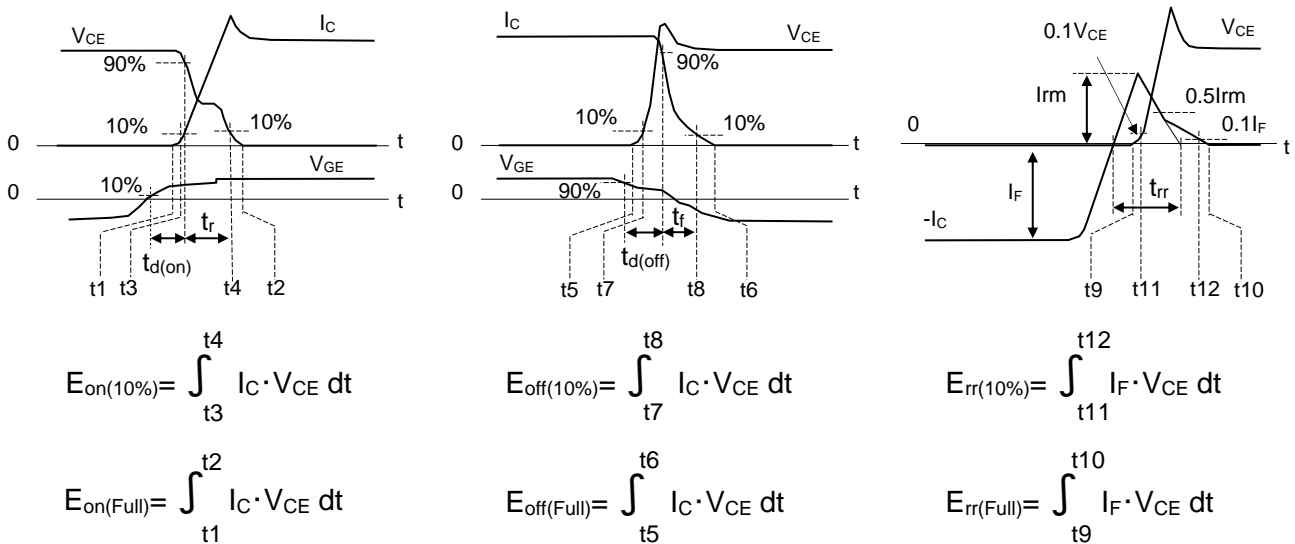
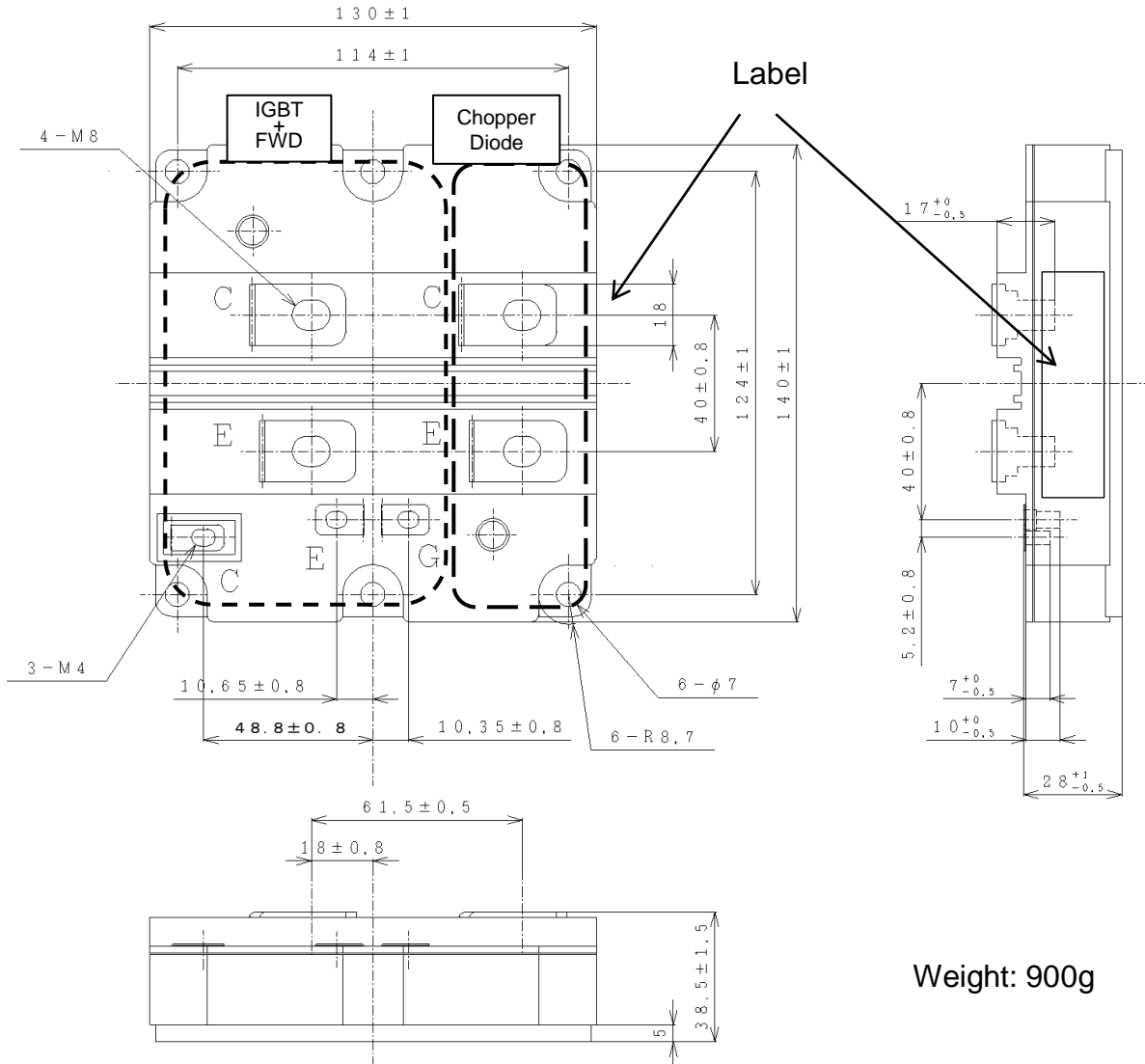


Fig.3 Definition of switching loss

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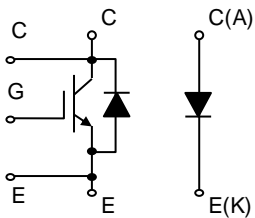
OUTLINE DRAWING

Unit in mm

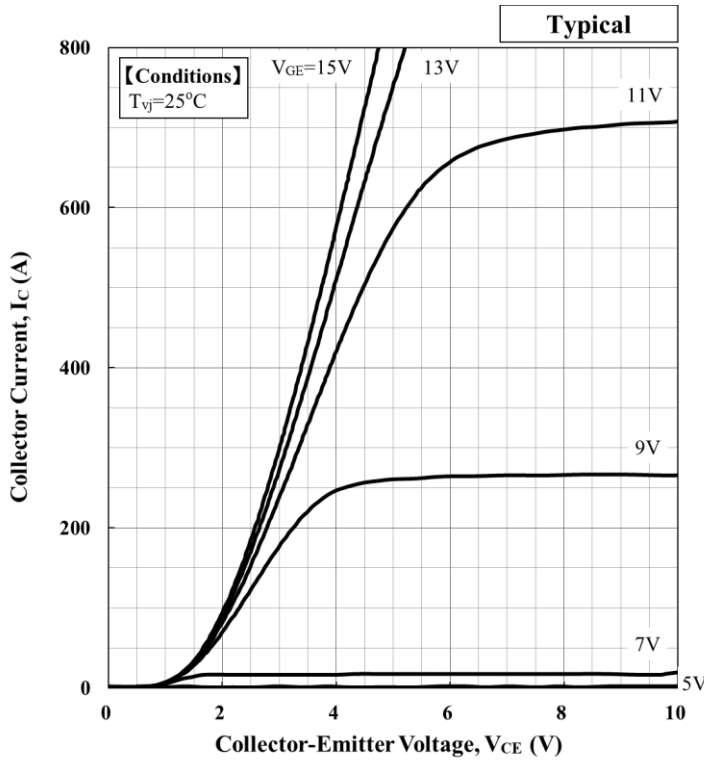


Weight: 900g

CIRCUIT DIAGRAM



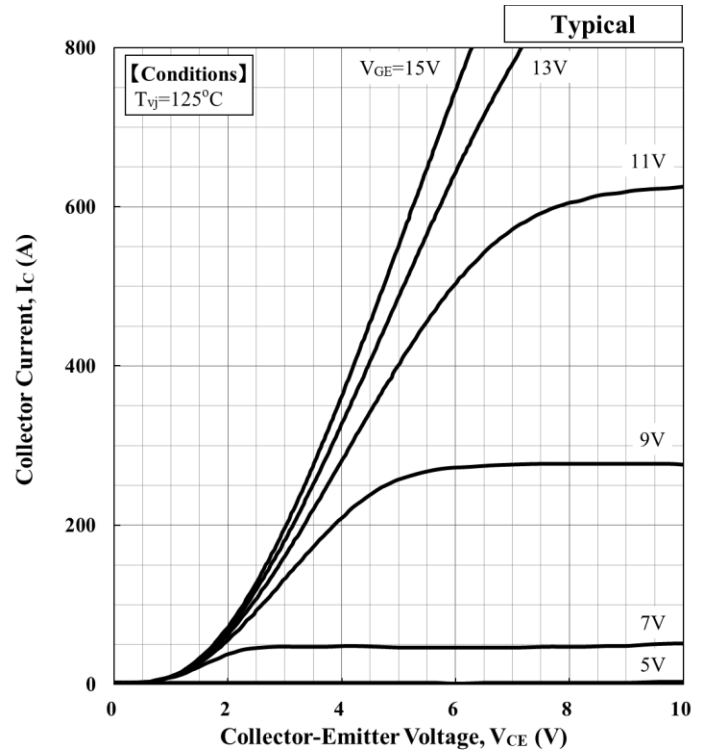
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$$V_{CE}(sat)[V] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	V _{GE} [V]	a ₃	a ₂	a ₁	a ₀
25	15	4.31E-09	-7.35E-06	7.41E-03	1.33E+00

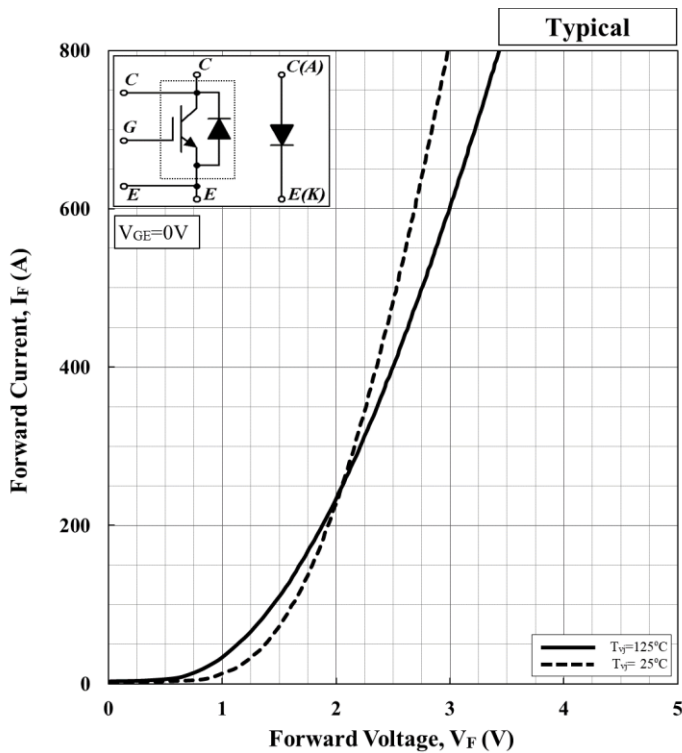
Collector Current vs. Collector Emitter Voltage



$$V_{CE}(sat)[V] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	V _{GE} [V]	a ₃	a ₂	a ₁	a ₀
125	15	6.25E-09	-1.02E-05	1.04E-02	1.28E+00

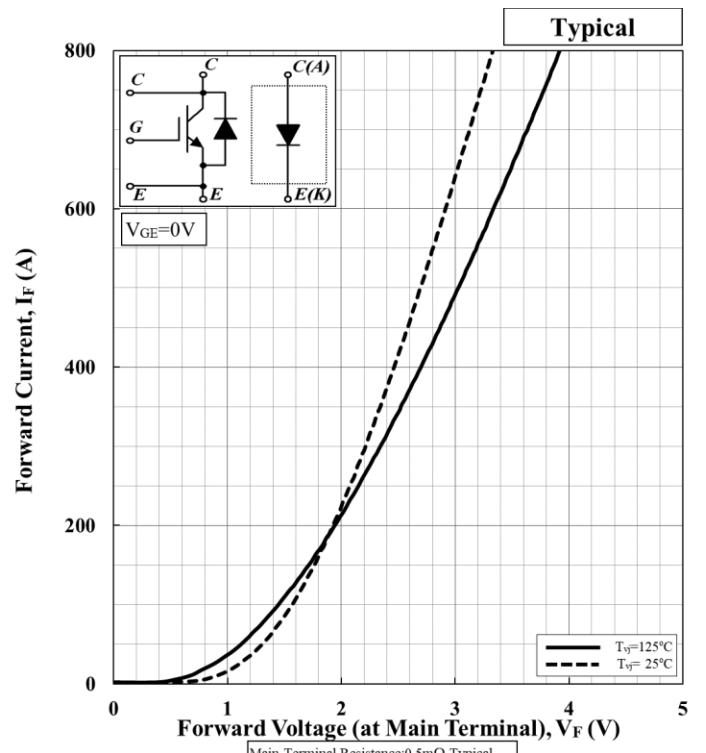
Collector Current vs. Collector Emitter Voltage



$$V_F[V] = a_3 \cdot |I_F|^3 + a_2 \cdot |I_F|^2 + a_1 \cdot |I_F| + a_0$$

Temp.[°C]	a ₃	a ₂	a ₁	a ₀
25	3.06E-09	-5.35E-06	4.60E-03	1.19E+00
125	3.42E-09	-6.22E-06	5.99E-03	8.92E-01

Forward Voltage of free-wheeling diode

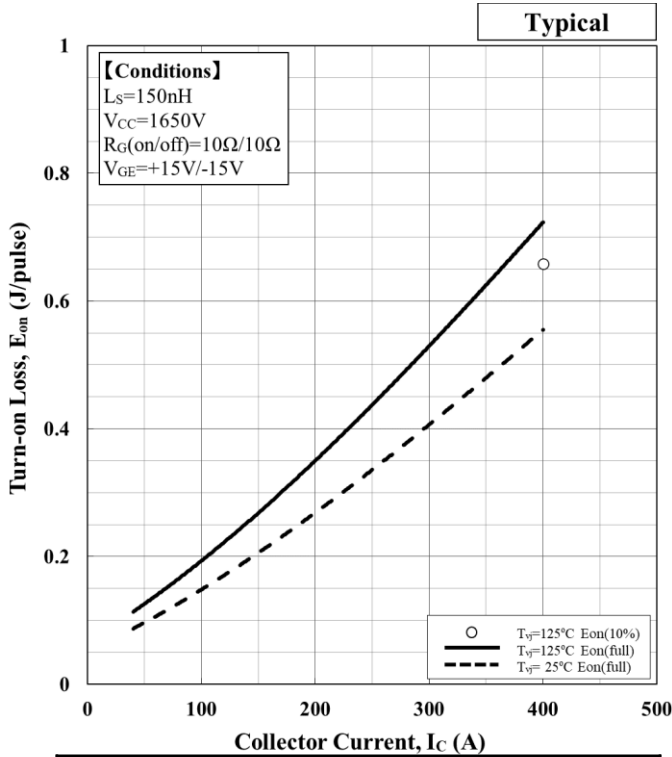


$$V_F[V] = a_3 \cdot |I_F|^3 + a_2 \cdot |I_F|^2 + a_1 \cdot |I_F| + a_0$$

Temp.[°C]	a ₃	a ₂	a ₁	a ₀
25	2.70E-09	-4.82E-06	4.93E-03	1.10E+00
125	3.24E-09	-5.94E-06	6.56E-03	8.29E-01

Forward Voltage of Chopper diode

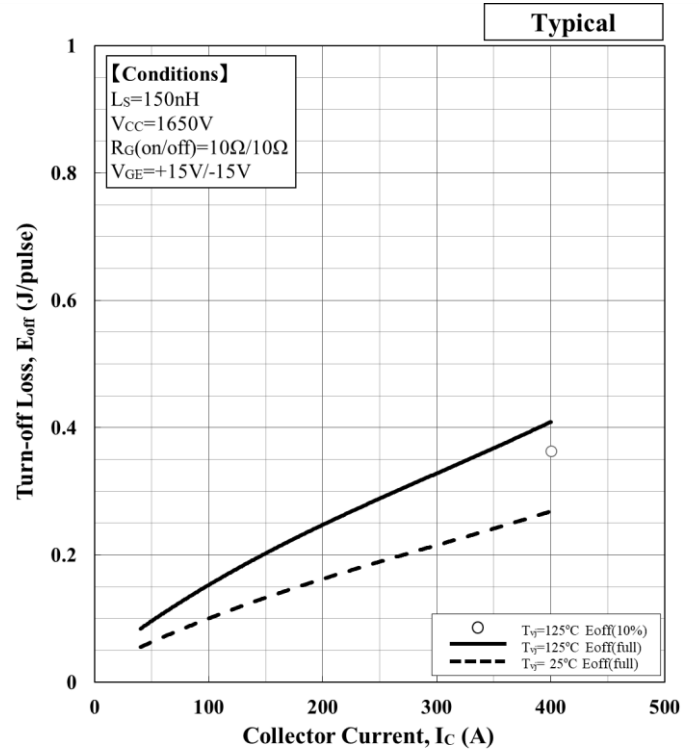
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$$E [J] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	a_3	a_2	a_1	a_0
25	-1.07E-09	1.51E-06	8.25E-04	5.18E-02
125	-1.40E-09	1.97E-06	1.08E-03	6.75E-02

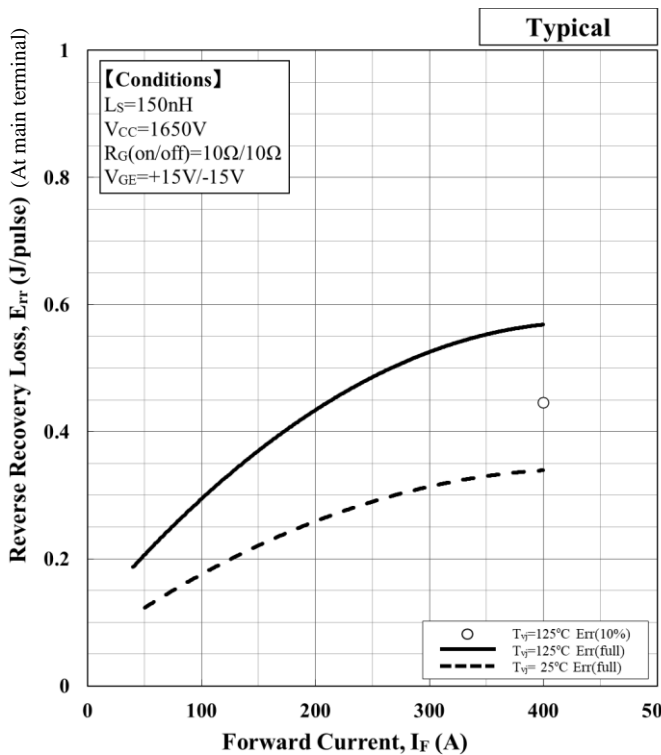
Turn-on loss vs. Collector current



$$E [J] = a_3 \cdot |I_c|^3 + a_2 \cdot |I_c|^2 + a_1 \cdot |I_c| + a_0$$

Temp.[°C]	a_3	a_2	a_1	a_0
25	1.48E-09	-1.34E-06	9.17E-04	2.05E-02
125	2.26E-09	-2.04E-06	1.40E-03	3.12E-02

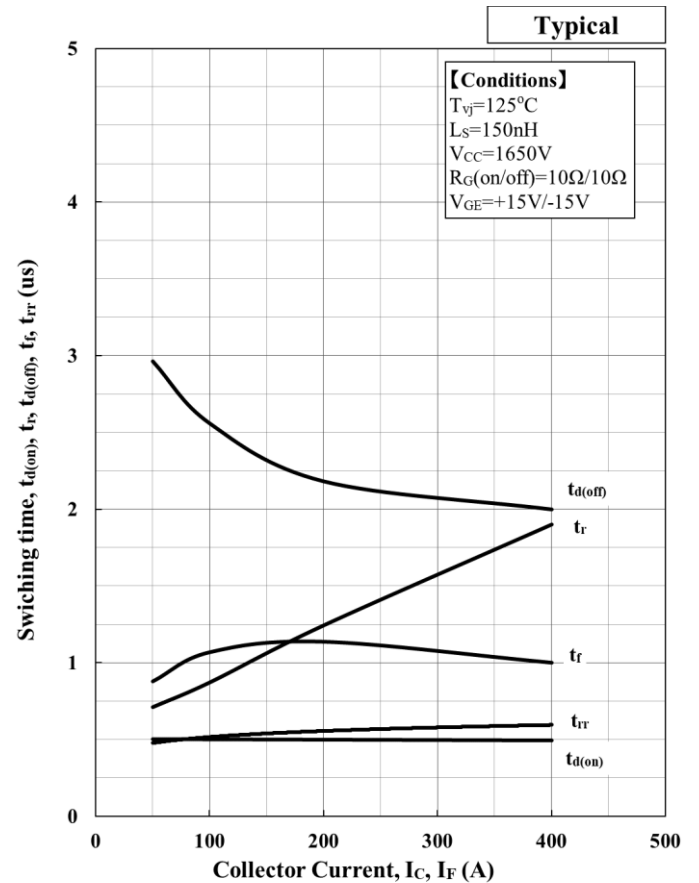
Turn-off loss vs. Collector current



$$E [J] = a_3 \cdot |I_F|^3 + a_2 \cdot |I_F|^2 + a_1 \cdot |I_F| + a_0$$

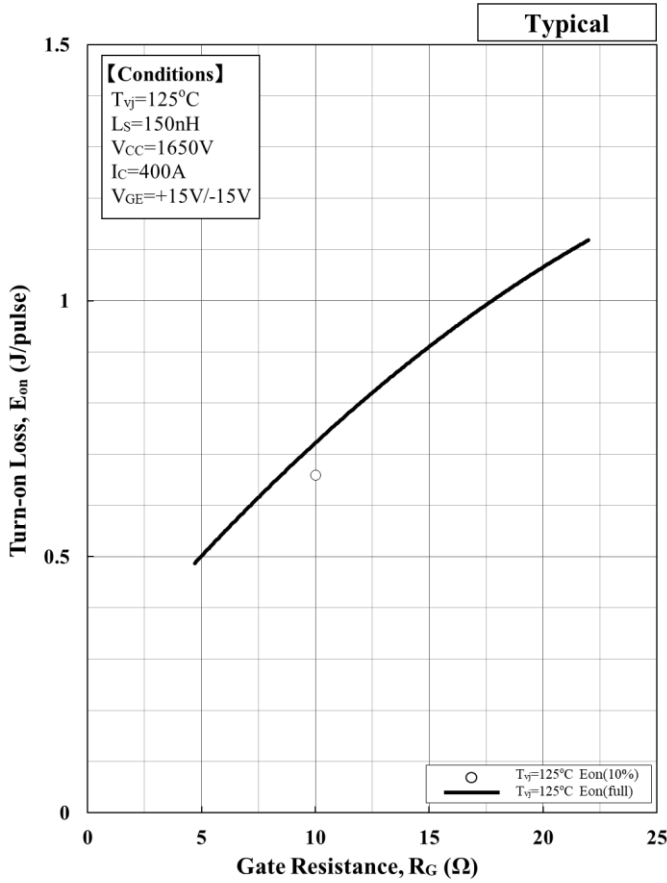
Temp.[°C]	a_3	a_2	a_1	a_0
25	0.00E+00	-1.45E-06	1.27E-03	6.33E-02
125	0.00E+00	-2.42E-06	2.12E-03	1.06E-01

Recovery loss vs. Forward Current(Chopper Diode)

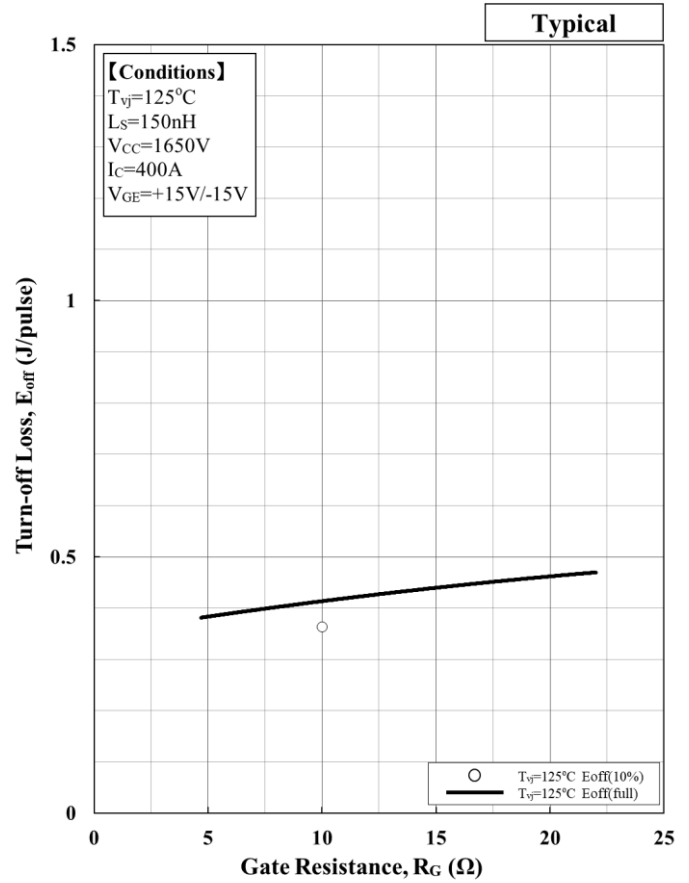


Switching time vs. Collector Current

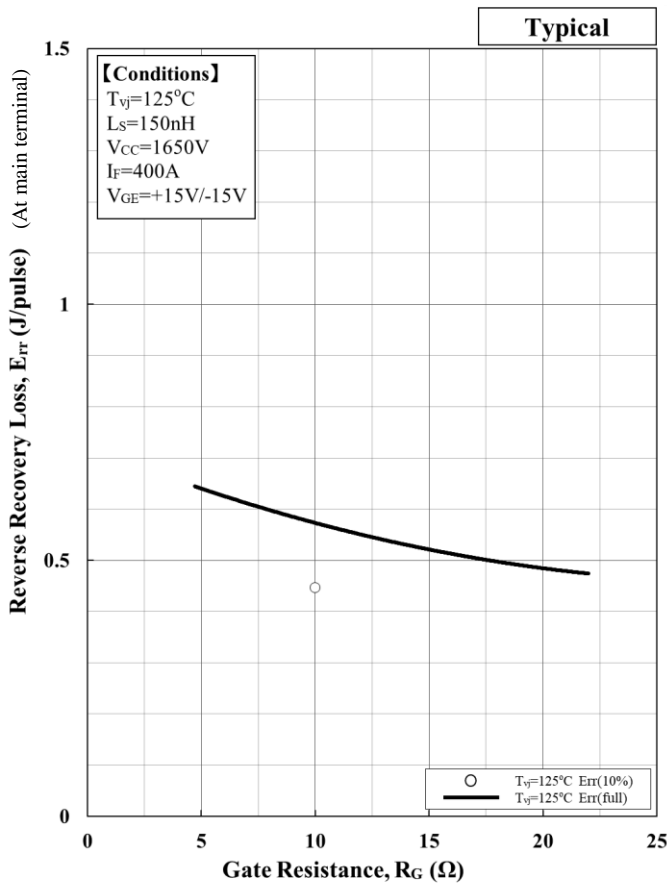
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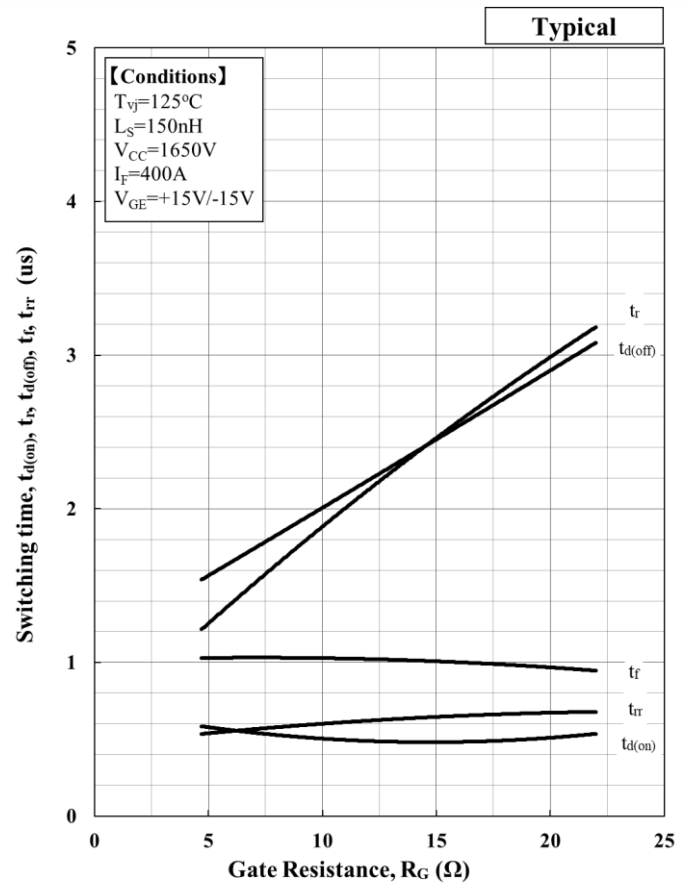
Turn-on loss vs. Gate Resistance



Turn-off loss vs. Gate Resistance

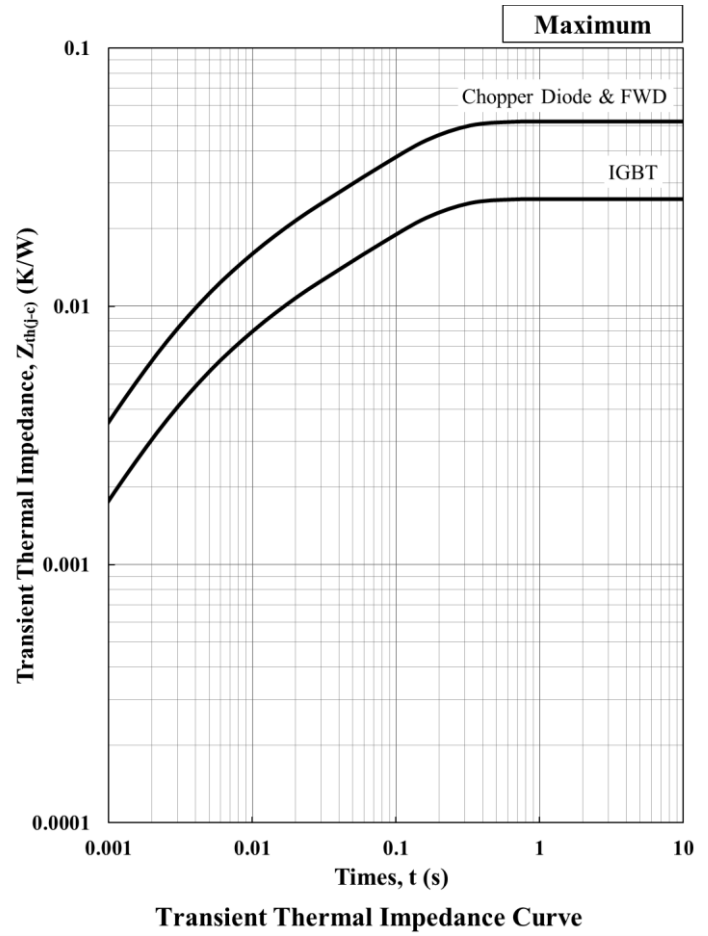
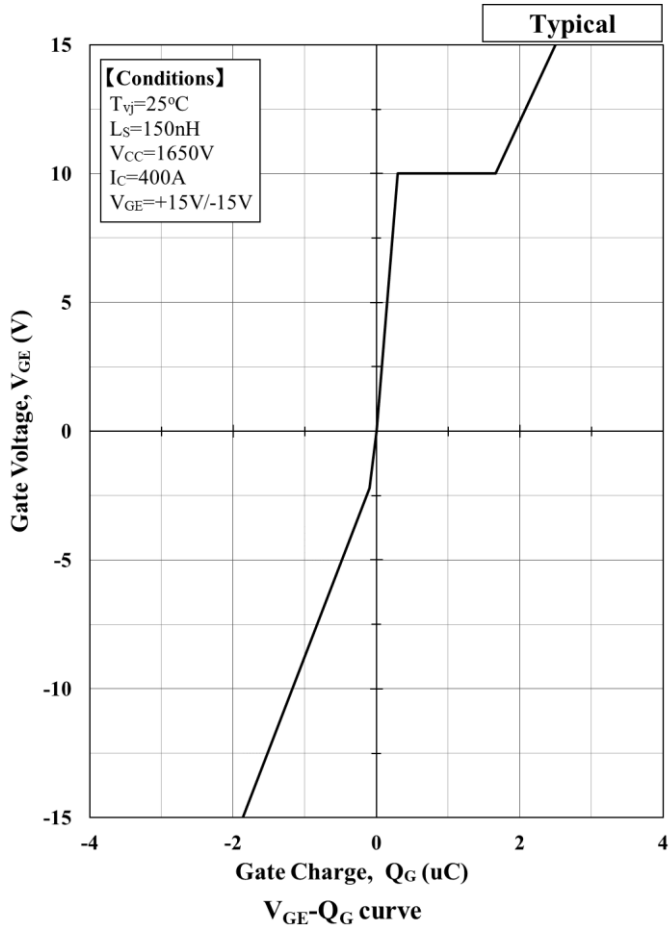


Reverse Recovery loss vs. Gate Resistance (Chopper Diode)



Switching time vs. Gate Resistance

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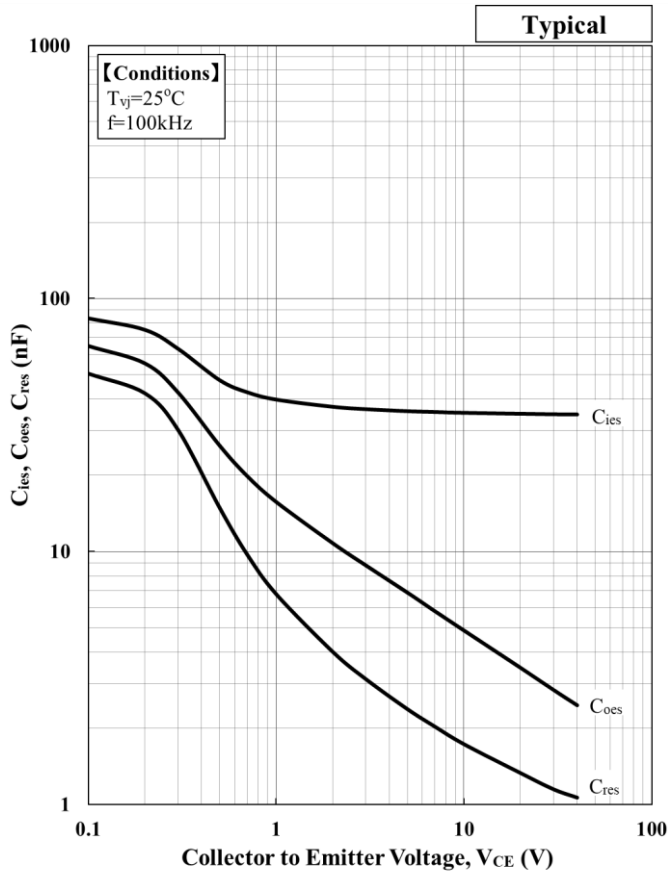
Foster model lumped circuit constant

n	1	2	3	4
R th, IGBT [n]	1.73E-02	2.67E-03	6.98E-05	6.00E-03
C th, IGBT [n]	6.43E+00	8.25E-01	2.23E+00	1.67E+00
R th, Diode [n]	3.46E-02	5.53E-03	1.29E-04	1.17E-02
C th, Diode [n]	3.20E+00	3.99E-01	1.21E+00	8.53E-01

Cauer model lumped circuit constant

n	1	2	3	4
R th, IGBT [n]	1.67E-03	4.95E-03	6.20E-03	1.32E-02
C th, IGBT [n]	4.14E-01	1.52E-01	1.47E+00	6.10E+00
R th, Diode [n]	3.53E-03	9.69E-03	1.24E-02	2.64E-02
C th, Diode [n]	2.07E-01	7.23E-02	7.50E-01	3.02E+00

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Capacitance vs. Collector to Emitter Voltage

Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder

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